Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/936,727	MIYOSHI ET AL.
Examiner	Art Unit
Krista M. Flanagan	2631

SEARCHED					
Class	Subclass	Date	Examiner		
375	144, 148, 346	12/2/2004	KMF		
370	286,342	12/2/2004	KMF		
370	441	12/2/2004	KMF		
375	130,142	12/10/2004	KMF		
375	147,150	12/10/2004	KMF		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1.		 		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East [(signal data symbol pulse) same (replica\$3 copy) same (cancel\$3 remove\$3) near5 (interference\$3 noise) and despread\$3]	12/2/2004	KMF
Inventorship	11/17/2004	KMF
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